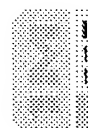


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**1 3D reconstruction of environments for virtual collaboration**

*Bajcsy, R.; Enciso, R.; Kamberova, G.; Nocera, L.; Sara, R.;*  
 Applications of Computer Vision, 1998. WACV '98. Proceedings., Fourth IEEE Workshop on , 19-21 Oct. 1998  
 Pages:160 - 167

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**3 A simulation-based validation of some improvements in automatic stereo-radargrammetry**

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